

### General Description

- Trench Power AlphaMOS-II technology
- Low  $R_{DS(ON)}$
- Low  $C_{iss}$  and  $C_{rss}$
- High Current Capability
- RoHS and Halogen Free Compliant

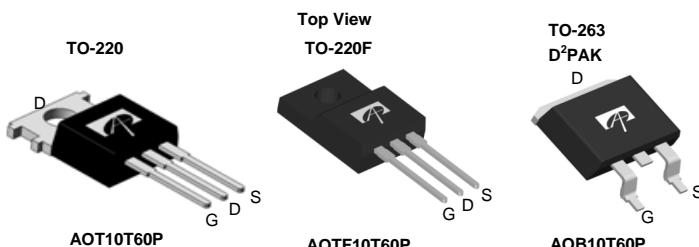
### Product Summary

$V_{DS} @ T_{j,max}$	700V
$I_{DM}$	40A
$R_{DS(ON),max}$	< 0.7Ω
$Q_{g,typ}$	26nC
$E_{oss} @ 400V$	3.5μJ

### Applications

- General Lighting for LED and CCFL
- AC/DC Power supplies for Industrial, Consumer, and Telecom

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT10T60PL	TO-220 Green	Tube	1000
AOB10T60PL	TO-263 Green	Tape & Reel	800
AOTF10T60P	TO-220F Pb Free	Tube	1000
AOTF10T60PL	TO-220F Green	Tube	1000

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOT(B)10T60P	AOTF10T60P	AOTF10T60PL	Units
Drain-Source Voltage	$V_{DS}$		600		V
Gate-Source Voltage	$V_{GS}$		$\pm 30$		V
Continuous Drain Current	$I_D$	10	10*	10*	A
$T_C=100^\circ\text{C}$		6.6	6.6*	6.6*	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$		40		
Avalanche Current <sup>C</sup> $L=1\text{mH}$	$I_{AR}$		10		A
Repetitive avalanche energy <sup>C</sup>	$E_{AR}$		50		mJ
Single pulsed avalanche energy <sup>G</sup>	$E_{AS}$		480		mJ
MOSFET dv/dt ruggedness	dv/dt		50		V/ns
Peak diode recovery dv/dt <sup>J</sup>			15		
Power Dissipation <sup>B</sup>	$P_D$	208	43	33	W
$T_C=25^\circ\text{C}$ Derate above 25°C		1.7	0.3	0.26	
Junction and Storage Temperature Range	$T_J, T_{STG}$		-55 to 150		°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	$T_L$		300		°C

Thermal Characteristics	Symbol	AOT(B)10T60P	AOTF10T60P	AOTF10T60PL	Units
Maximum Junction-to-Ambient <sup>A,D</sup>	$R_{θJA}$	65	65	65	°C/W
Maximum Case-to-sink <sup>A</sup>	$R_{θCS}$	0.5	--	--	°C/W
Maximum Junction-to-Case	$R_{θJC}$	0.6	2.9	3.8	°C/W

\* Drain current limited by maximum junction temperature.

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	600			V
		$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=150^\circ\text{C}$		700		
$BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$		0.56		$\text{V}^\circ\text{C}$
		$V_{DS}=600\text{V}, V_{GS}=0\text{V}$			1	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=480\text{V}, T_J=125^\circ\text{C}$			10	$\mu\text{A}$
		$V_{DS}=600\text{V}, V_{GS}=0\text{V}$			$\pm 100$	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$				nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$	3	4.3	5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5\text{A}$		0.58	0.7	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=40\text{V}, I_D=5\text{A}$		8.8		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.74	1	V
$I_S$	Maximum Body-Diode Continuous Current				10	A
$I_{SM}$	Maximum Body-Diode Pulsed Current <sup>C</sup>				40	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=100\text{V}, f=1\text{MHz}$		1595		pF
$C_{oss}$	Output Capacitance			56		pF
$C_{o(er)}$	Effective output capacitance, energy related <sup>H</sup>	$V_{GS}=0\text{V}, V_{DS}=0 \text{ to } 480\text{V}, f=1\text{MHz}$		42		pF
$C_{o(tr)}$	Effective output capacitance, time related <sup>I</sup>			74		pF
$C_{rss}$	Reverse Transfer Capacitance	$V_{GS}=0\text{V}, V_{DS}=100\text{V}, f=1\text{MHz}$		11		pF
$R_g$	Gate resistance	$f=1\text{MHz}$		1.7		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=480\text{V}, I_D=10\text{A}$		26	40	nC
$Q_{gs}$	Gate Source Charge			8.1		nC
$Q_{gd}$	Gate Drain Charge			8.2		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=300\text{V}, I_D=10\text{A}, R_G=25\Omega$		42		ns
$t_r$	Turn-On Rise Time			54		ns
$t_{D(off)}$	Turn-Off Delay Time			52		ns
$t_f$	Turn-Off Fall Time			24		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=10\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$		497		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=10\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$		7.3		$\mu\text{C}$

A. The value of  $R_{\text{aja}}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{aja}}$  is the sum of the thermal impedance from junction to case  $R_{\text{ajc}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G.  $L=60\text{mH}, I_{AS}=4\text{A}, V_{DD}=150\text{V}, R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$ .

H.  $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{(BR)DSS}$ .

I.  $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{(BR)DSS}$ .

J.  $I_{SD} \leq I_D, dI/dt \leq 200\text{A}/\mu\text{s}, V_{DD}=400\text{V}, T_J \leq T_{J(\text{MAX})}$ .

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

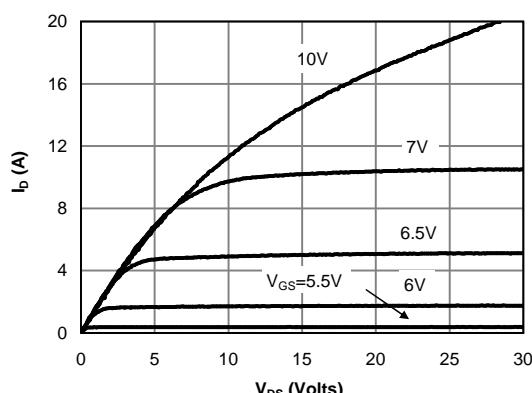


Figure 1: On-Region Characteristics

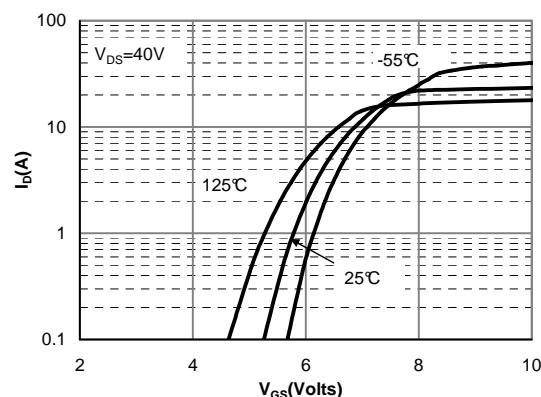


Figure 2: Transfer Characteristics

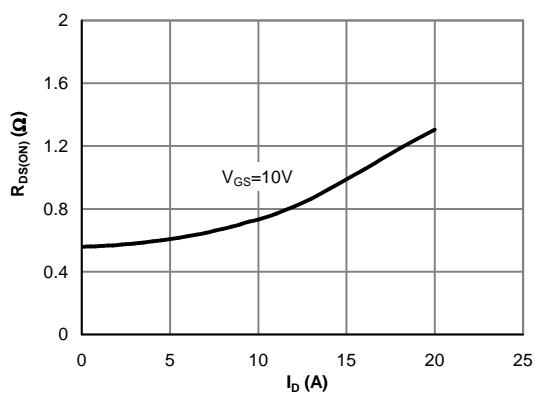


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

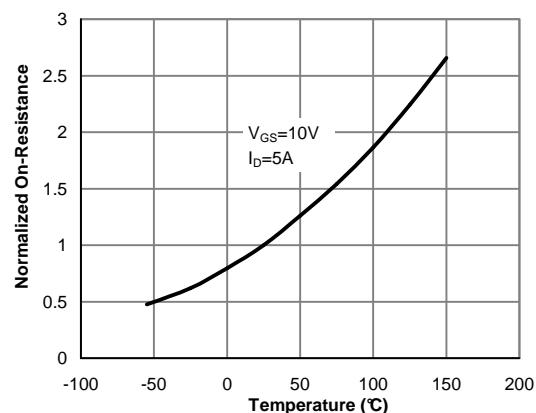


Figure 4: On-Resistance vs. Junction Temperature

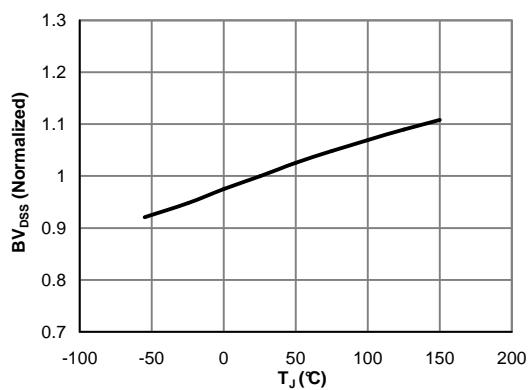


Figure 5: Break Down vs. Junction Temperature

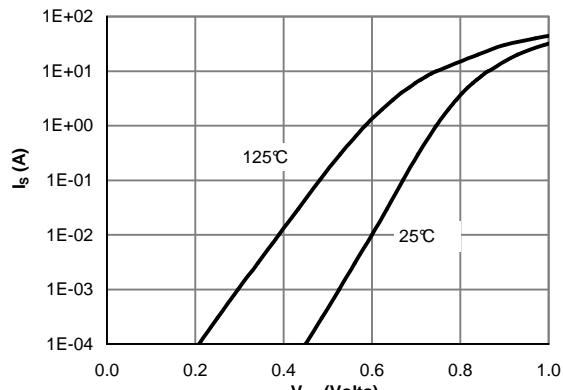


Figure 6: Body-Diode Characteristics

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

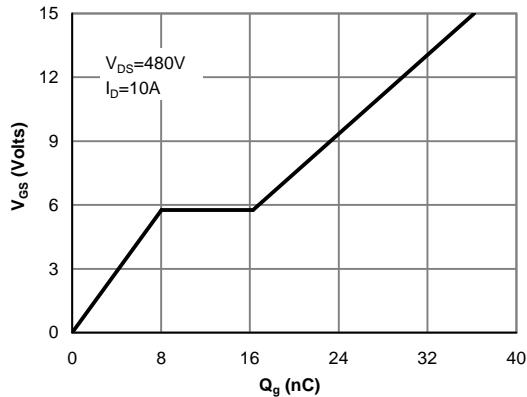


Figure 7: Gate-Charge Characteristics

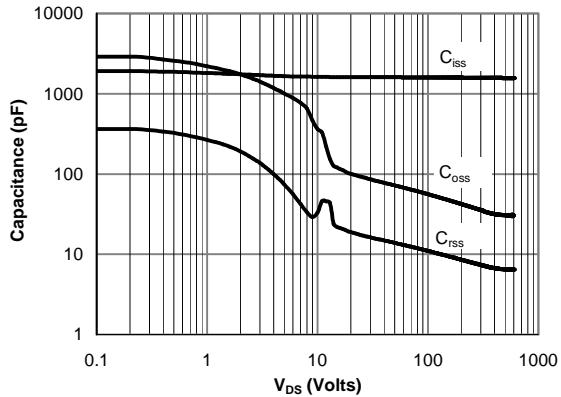


Figure 8: Capacitance Characteristics

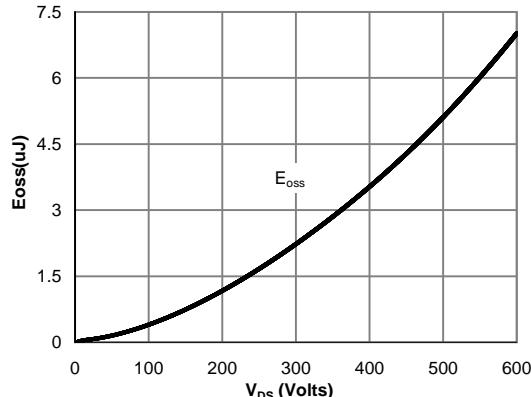


Figure 9: Coss stored Energy

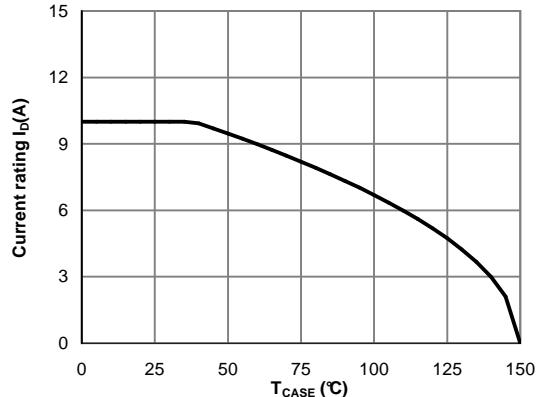


Figure 10: Current De-rating (Note F)

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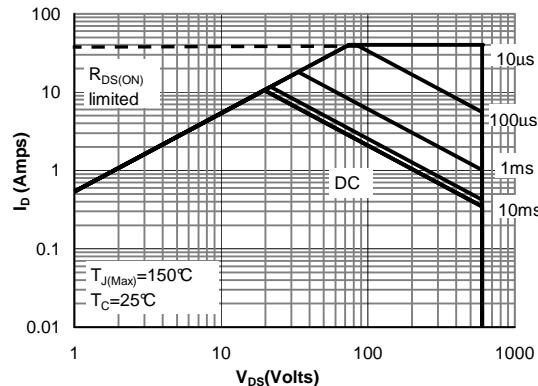


Figure 11: Maximum Forward Biased Safe Operating Area for TO-220/TO-263 (Note F)

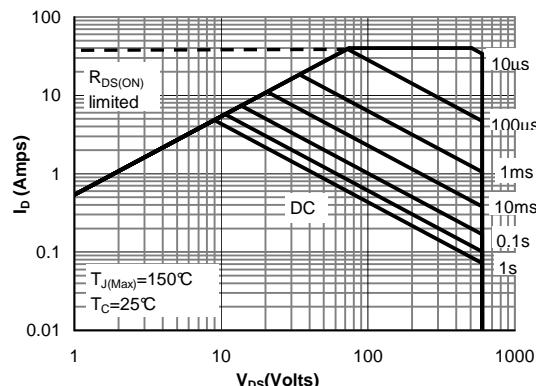


Figure 12: Maximum Forward Biased Safe Operating Area for TO-220F Pb Free (Note F)

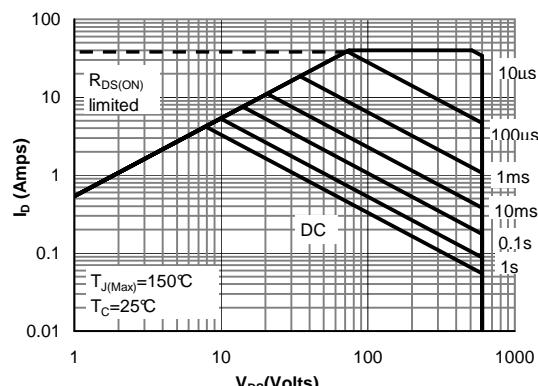


Figure 13: Maximum Forward Biased Safe Operating Area for TO-220F Green (Note F)

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

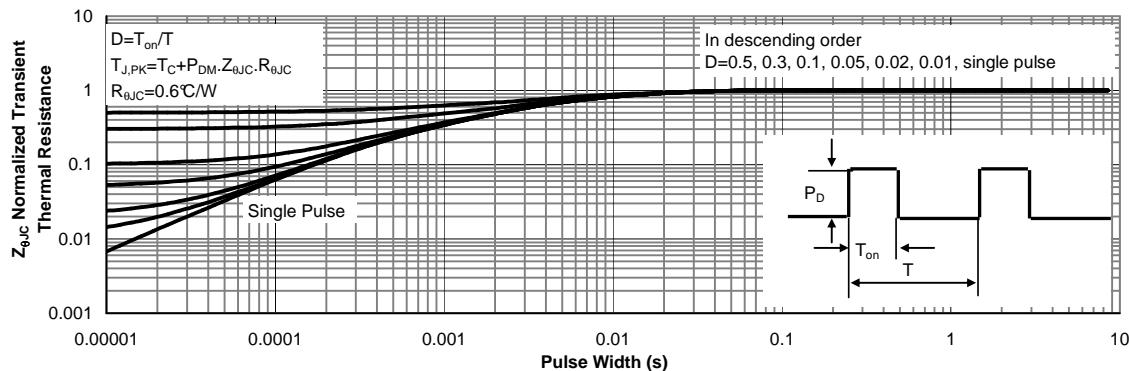


Figure 14: Normalized Maximum Transient Thermal Impedance for TO-220/TO-263 (Note F)

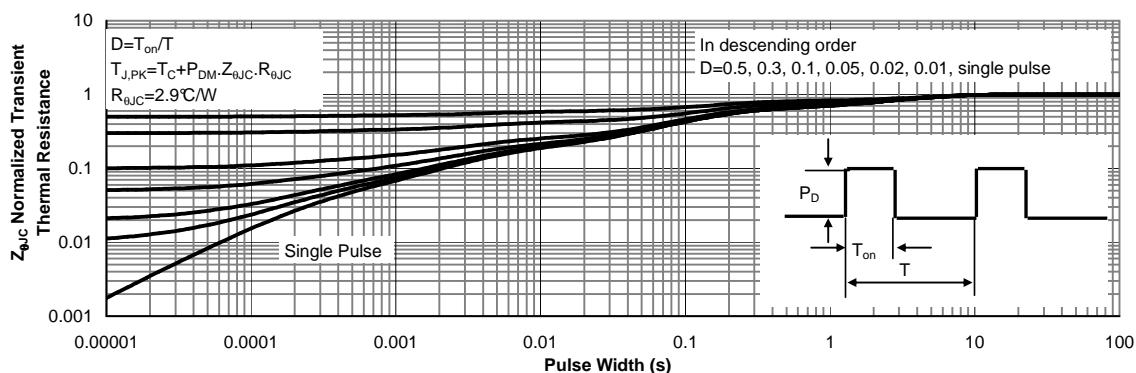


Figure 15: Normalized Maximum Transient Thermal Impedance for TO-220F Pb Free (Note F)

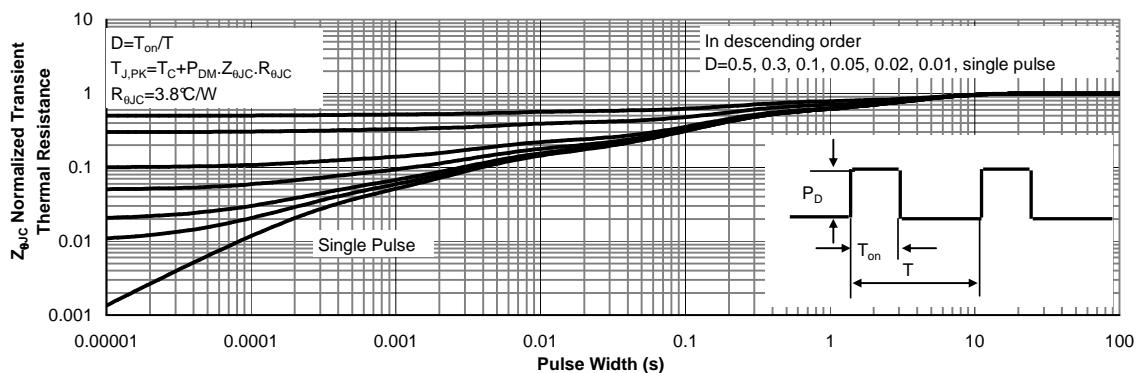
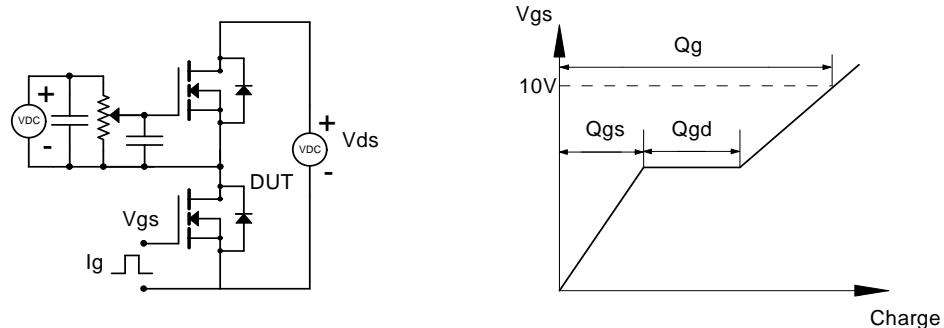
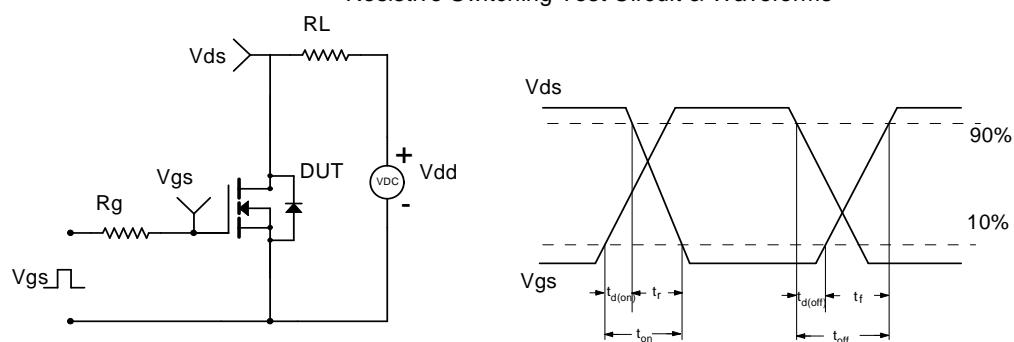


Figure 16: Normalized Maximum Transient Thermal Impedance for TO-220F Green (Note F)

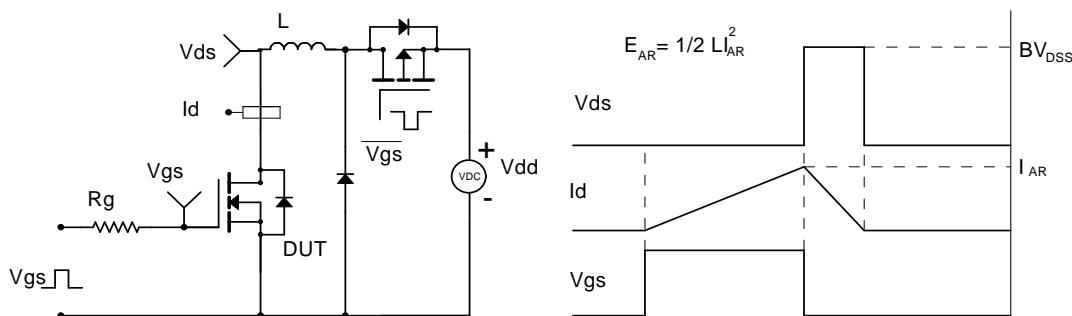
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

